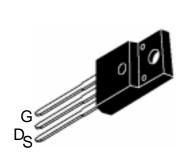
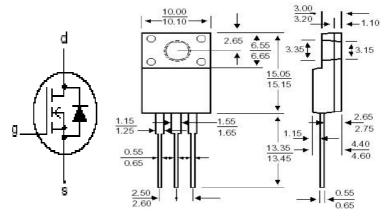
## **Description**

## **Mechanical Dimensions**

REGAOFP







DIMENSION IN MM

### **GENERAL DESCRIPTION**

This Power MOSFET is designed for low voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

### **FEATURES**

- ♦ Silicon Gate for Fast Switching Speeds
- ◆ Low R<sub>DS(on)</sub> to Minimize On-Losses. Specified at Elevated Temperature
- ♦ Rugged SOA is Power Dissipation Limited
- Source-to-Drain Characterized for Use With Inductive Loads

### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit	
rain to Current — Continuous		18	Α	
<ul><li>Pulsed</li></ul>	I <sub>DM</sub>	72		
Gate-to-Source Voltage — Continue		±20	V	
<ul><li>Non-repetitive</li></ul>	$V_{GSM}$	±40	V	
Total Power Dissipation	P <sub>D</sub>	125	W	
Derate above 25℃		1.00	W/°C	
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	$^{\circ}\mathbb{C}$	
Single Pulse Drain-to-Source Avalanche Energy $-$ T <sub>J</sub> = 25 $^{\circ}$ C	E <sub>AS</sub>	224	mJ	
$(V_{DD} = 100V, V_{GS} = 10V, I_{L} = 18A, L = 1.38mH, R_{G} = 25\Omega)$				
Thermal Resistance — Junction to Case	$\theta_{JC}$	1.00	°C/W	
<ul> <li>Junction to Ambient</li> </ul>	$\theta_{JA}$	62.5		
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	$^{\circ}\!\mathbb{C}$	

(1) Pulse Width and frequency is limited by TJ(max) and thermal response

### **ELECTRICAL CHARACTERISTICS**

Unless otherwise specified,  $T_J = 25^{\circ}C$ .

			IRF640			
Characteristic		Symbol	Min	Тур	Max	Units
Drain-Source Breakdown Voltage		V <sub>(BR)DSS</sub>	200			V
$(V_{GS} = 0 \text{ V}, I_D = 250 \ \mu \text{ A})$						
Drain-Source Leakage Current		I <sub>DSS</sub>				mA
$(V_{DS} = Rated V_{DSS}, V_{GS} = 0 V)$					0.025	
$(V_{DS} = 0.8Rated V_{DSS}, V_{GS} = 0 V, T_{J} = 125^{\circ}C)$					1.0	
Gate-Source Leakage Current-Forward		I <sub>GSSF</sub>			100	nA
$(V_{gsf} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate-Source Leakage Current-Reverse		I <sub>GSSR</sub>			100	nA
$(V_{gsr} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate Threshold Voltage		V <sub>GS(th)</sub>	2.0		4.0	V
$(V_{DS} = V_{GS}, I_{D} = 250 \ \mu A)$						
Static Drain-Source On-Resistance (V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10A) *		R <sub>DS(on)</sub>			0.18	Ω
Drain-Source On-Voltage (V <sub>GS</sub> = 10 '	urce On-Voltage (V <sub>GS</sub> = 10 V)				6.0	V
$(I_D = 5.0 \text{ A})$						
Forward Transconductance ( $V_{DS} = 5$	0 V, I <sub>D</sub> = 10 A) *	<b>g</b> FS	6.8			mhos
Input Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz)	C <sub>iss</sub>			1600	pF
Output Capacitance		C <sub>oss</sub>			750	pF
Reverse Transfer Capacitance		C <sub>rss</sub>			300	pF
Turn-On Delay Time	$(V_{DD} = 30 \text{ V}, I_{D} = 10 \text{ A},$ $V_{GS} = 10 \text{ V},$ $R_{G} = 4.7\Omega) *$	t <sub>d(on)</sub>			30	ns
Rise Time		t <sub>r</sub>			60	ns
Turn-Off Delay Time		t <sub>d(off)</sub>			80	ns
Fall Time		t <sub>f</sub>			60	ns
Total Gate Charge	(V <sub>DS</sub> = 0.8Rated V <sub>DSS</sub> , I <sub>D</sub> = Rated I <sub>D</sub> , V <sub>GS</sub> = 10 V)*	Qg		36	63	nC
Gate-Source Charge		$Q_{gs}$		16		nC
Gate-Drain Charge		$Q_{gd}$		26		nC
Internal Drain Inductance		L <sub>D</sub>		4.5		nH
(Measured from the drain lead 0.2	5" from package to center of die)					
Internal Drain Inductance		Ls		7.5		nH
(Measured from the source lead 0.25" from package to source bond pad)						
SOURCE-DRAIN DIODE CHARACT	TERISTICS					
Forward On-Voltage(1)	(I <sub>S</sub> = Rated I <sub>D</sub> ,	V <sub>SD</sub>			1.5	V
Forward Turn-On Time		t <sub>on</sub>		**		ns
Reverse Recovery Time	$d_{IS}/d_t = 100A/\mu s)$	t <sub>rr</sub>		450		ns

<sup>\*</sup> Pulse Test: Pulse Width  $\ \le 300 \mu s$ , Duty Cycle  $\ \le 2\%$ 

<sup>\*\*</sup> Negligible, Dominated by circuit inductance



### TYPICAL ELECTRICAL CHARACTERISTICS

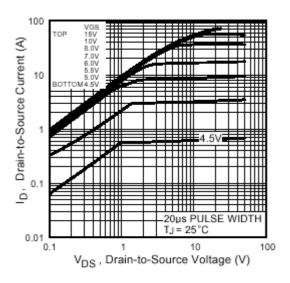


Fig 1. Typical Output Characteristics

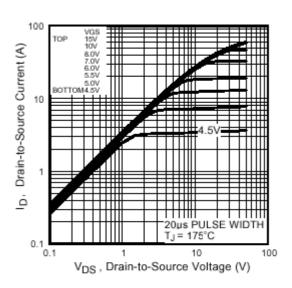


Fig 2. Typical Output Characteristics

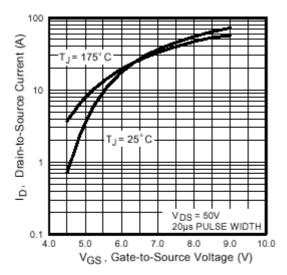


Fig 3. Typical Transfer Characteristics

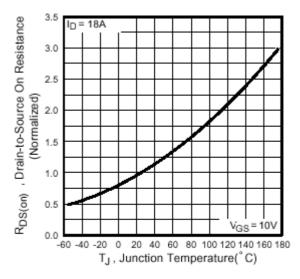


Fig 4. Normalized On-Resistance Vs. Temperature



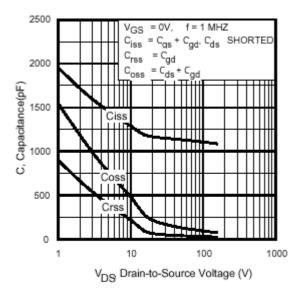


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

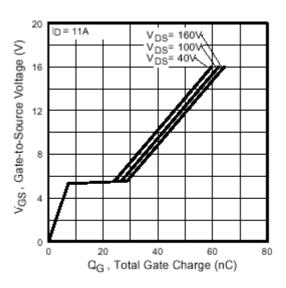


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

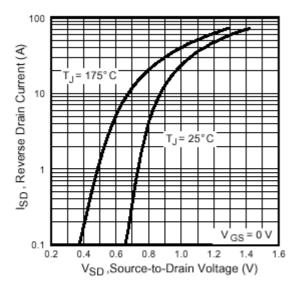


Fig 7. Typical Source-Drain Diode Forward Voltage

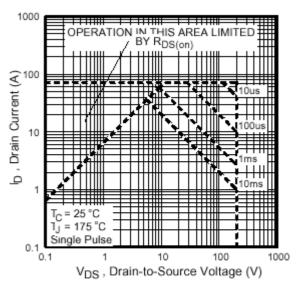


Fig 8. Maximum Safe Operating Area



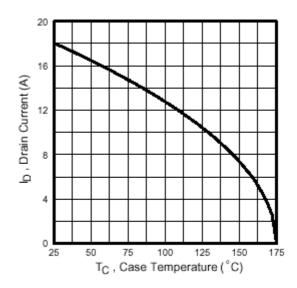


Fig 9. Maximum Drain Current Vs. Case Temperature

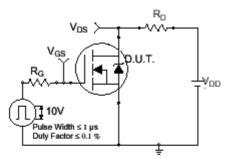


Fig 10a. Switching Time Test Circuit

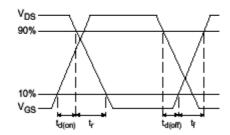


Fig 10b. Switching Time Waveforms

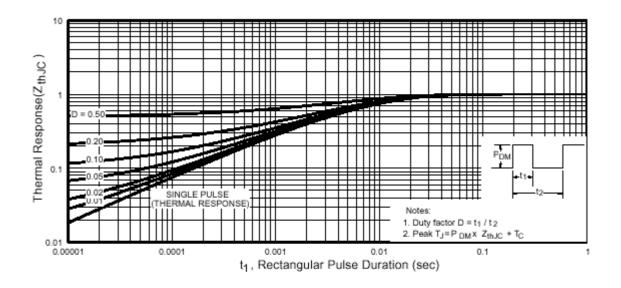


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case